

Form PTO-1449 U.S. Department of Commerce  
(REV. 2-82) Patent and Trademark OfficeAtty. Docket No.  
036179/US/2-475387-30Serial No.  
10/577,562**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**  
(Use several sheets if necessary)Applicant(s)  
Seok-Hyun Yun et al.Filing Date  
April 27, 2006Confirmation No.  
3634**U.S. PATENT DOCUMENTS**

*Exam. Init.	Document No.							Date	Name	Class	Subclass	Filing Date if Appropriate
	6	0	2	0	9	6	3	February 1, 2000	Dimarzio et al ΩΩΩΩ			
	6	3	4	1	0	3	6	January 27, 2002	Teamev et al. ΩΩΩΩ			
	6	3	9	6	9	4	1	May 28, 2002	Bacus, James W. et al. ΩΩΩΩΩΩ			
200	5	0	1	8	2	0	1	January 27, 2005	De Boer, Johannes F. Et al ΩΩΩΩΩΩ			
	6	5	6	7	5	8	5	May 20, 2003	Martin et al ΩΩΩΩΩΩΩΩ			
	5	9	2	6	5	9	2	July 20, 1999	Martin et al. ΩΩΩΩΩΩΩΩ			
	7	2	6	7	4	9	4	September 11, 2007	Hongyu et al. ΩΩΩΩΩΩΩΩ			
	5	0	7	5	6	0	7	November 2, 1999	Podoleanu et al.			
	5	7	4	1	3	6	4	August 31, 1993	Kimura et al. ΩΩΩΩΩΩΩΩ Ω			
	5	0	1	0	8	3	9	June 8, 1999	Erskine et al ΩΩΩΩΩΩΩΩ Ω			
200	7	0	7	0	4	9	6	March 29, 2007	Gweon et al. ΩΩΩΩΩΩΩΩ Ω			
	4	8	2	7	0	0	7	May 9, 1989	Tashiro et al. ΩΩΩΩΩΩΩΩ ΩΩ			
	4	9	9	8	9	7	2	March 12, 1991	Chin et al. ΩΩΩΩΩΩΩΩ ΩΩ			
	5	7	3	0	7	3	1	March 24, 1998	Mollenauer et al. ΩΩΩΩΩΩΩΩ ΩΩ			

Examiner

Date Considered

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ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /MAL/

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200	2	1	2	0	1	3	7	June 26, 2003	Pawluczuk et al. <del>YYY</del>			
200	2	0	9	1	3	2	2	July 11, 2002	Chaiken et al. <del>YY</del>			
2005	0	1	6	5	3	0	3	July 28, 2005	Kleen Martin et al. <del>YYY</del>			
200	2	0	5	2	5	4	7	May 2, 2002	Toida Masahiro <del>YYY</del>			
200	4	0	0	2	6	5	0	January 1, 2004	Mandrusov Evgenia et al. <del>YYY</del>			
200	2	0	8	2	1	0	5	May 1, 2003	Fischman Alan et al. <del>YYY</del>			
5	3	0	4	1	7	2		April 10, 1994	Kittrell Carter et al. <del>YYY</del>			
7	3	3	6	3	6	6		February 26, 2008	Choma et al.			
7	0	1	9	8	3	8		March 28, 2006	Izatt et al.			
6	3	7	4	1	2	8		April 16, 2002	Toida et al.			
6	4	7	7	4	0	3		November 5, 2002	Eguchi et al.			
5	5	5	5	8	8	7		September 10, 1996	Miyagawa et al. <del>YYYY</del>			
200	5	0	5	7	7	5	6	March 17, 2005	Fang-Yen et al. <del>YYYY</del>			
4	5	8	5	3	4	9		April 29, 1986	Gross Daniel et al.			
5	7	8	5	6	5	1		July 28, 1998	Baker et al. <del>YYYY</del>			

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		5	8	1	7	1	4	4	October 6, 1998	Gregory Kenton et al. <del>XXXX</del>			
	2003	0	1	7	4	3	3	9	September 18, 2003	Feldchtein et al.			
	200	3	0	3	0	8	1	6	February 13, 2003	Eom Tae Bong et al.			
	200	2	0	5	7	4	3	1	May 16, 2002	Fateley William G. et al			
	2005	0	0	5	7	6	8	0	March 2005	Agan, Martin J. <del>XXXXXX</del>			
		5	3	4	8	0	0	3	September 1994	Caro, Richard G. <del>XXXXXX</del>			
		5	2	5	0	1	8	6	October 1993	Dollinger et al. <del>XXXXXX</del>			
		5	3	9	4	2	3	5	February 1995	Takeuchi et al. <del>XXXXXX</del>			
		6	2	4	9	3	8	1	June 2001	Suganuma, Hiroshi <del>XXXXXX</del>			
		6	9	0	9	1	0	5	June 2005	Heintzmann et al. <del>XXXXXXXX</del>			
		7	2	3	6	6	3	7	June 2007	Sirohey et al. <del>XXXXXXXX</del>			
	2002	0	0	4	8	0	2	5	April 2002	Takaoka, Hideyuki €			
	2002	0	1	6	8	1	5	8	November 2002	Furusawa et al. €€			
		6	7	5	7	4	6	7	June 2004	Rogers, Philip L. €€			
		5	5	6	6	2	6	7	October 1996	Neuberger, Wolfgang			

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		Document No.							Date	Country	Class	SubClass	Translator	
		7	9	0	0	8	4	1					Yes	No
									October 18, 1979	WIPO ΩΩ				
									January 8, 1998	WIPO ΩΩΩ				
	200	2	0	8	4	2	6	3	October 24, 2002	WIPO ΩΩΩΩΩ				
	200	4	0	5	7	2	6	6	July 8, 2004	WIPO ΩΩΩΩΩ				
	200	1	0	2	7	6	7	9	April 10, 2001	WIPO ΩΩΩΩΩΩ				
	200	3	0	4	6	6	3	6	June 5, 2003	WIPO ΩΩΩΩΩΩ				
	200	6	0	0	4	7	4	3	January 12, 2006	WIPOΩΩΩΩΩ				
		9	2	0	1	9	6	6	February 6, 1992	WIPO¥				
		6	0	7	3	4	0	5	April 25, 1985	Japan¥				
		5	5	0	9	4	1	7	November 22, 1993	Japan¥				
		2	7	3	8	3	4	3	August 30, 1995	France¥				
	200	3	0	6	2	0	0	2	July 31, 2003	WIPO				
	200	5	0	4	7	8	1	2	May 26, 2005	WIPO				
		2	2	9	8	0	5	4	August 21, 1996	Great Britain¥¥¥¥				
	200	6	1	2	4	8	6	0	November 23, 2006	WIPO ¥¥¥¥				
	200	2	2	1	4	1	2	7	July 31, 2002	Japan¥¥¥¥¥¥				
		0	1	0	1	1	1	1	January 2001	WIPO €€				

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~~XXXXXX~~ Reference cited in Office Action dated August 6, 2009 for U.S. Patent application no. 11/624,455  
~~XXXXXX~~ Reference cited in Office Action dated May 15, 2009 for U.S. Patent application no. 11/537,123  
~~E~~ Reference cited in Office Action dated April 17, 2009 for U.S. Patent application no. 11/537,343  
~~EE~~ Reference cited in Office Action dated April 15, 2009 for U.S. Patent application no. 12/205,775

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Database Biosis Biosciences Information Service, Philadelphia, PA, US; October 2006, Yelin D. et al: "Three Dimensional Miniature Endoscopy" ΩΩ

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Application No. PCT/US2006/058277 ~~XXXXXXXXXX~~

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Application No. PCT/US2008/081834 ~~XXXXXXXXXX~~

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Application No. PCT/US2008/074863

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4840-3838-4388\1

Examiner /Michael A. Lyons/

Date Considered 10/08/2009

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